Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/517,095	TSATSANIS ET AL.	
Examiner	Art Unit	
Sai-Ming Chan	2616	

SEARCHED					
	SEARCHED				
Class	Subclass	Date	Examiner		
370	260	12/17/2007	sc		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	12/17/2007	sc	
Inventor and Assignee search in PALM EXPO and EAST	12/17/2007	sc	
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